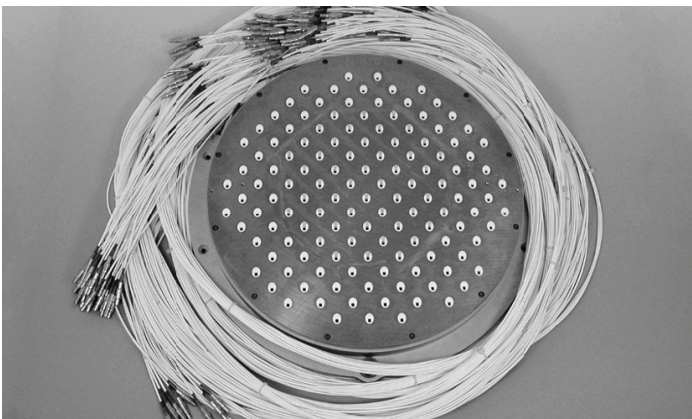
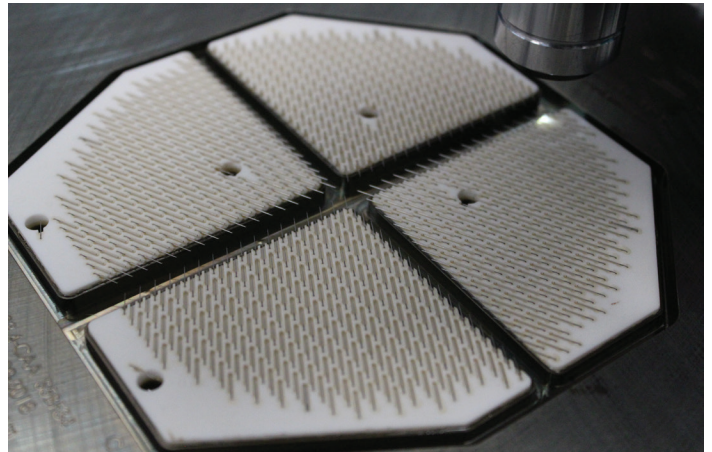
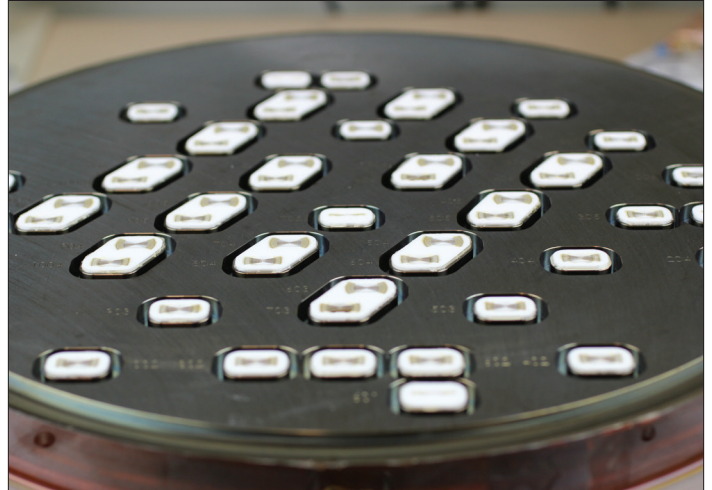


T300 BUTTONTILE™

Multi-Site Wafer Level Reliability and Production Burn-In

T300 ButtonTiles™ are optimized for high-density, multi-site, long-term, temperature-compensated wafer level reliability testing. The ceramic tiles match the expansion characteristics of a wafer at high temperatures, so users don't need to constantly monitor in-progress testing.

ButtonTiles™ can accommodate up to 10,000 probes respectively. The standard operating temperature range is -65° to 300°C standard, with a high temperature option up to 400°C. With the T300 ButtonTile™, collect accurate and reliable data from your entire wafer.



LIGHTS-OUT
HIGH-DENSITY
WAFER LEVEL
RELIABILITY
TEST